

TECHNICAL SPEC FOR Characterization system

System Model:

SDI FAaSt 230 DP+SPV

Wafer size: 6 inch

SPV2	Metrology & Inspection	meas Fe	FAast-230-DP-SPV	PB6	99-110214	1999
------	------------------------	---------	------------------	-----	-----------	------

SECS/GEM:

Vintage: 1999

Missing parts: none

Defected parts: none